

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V _{DSS}	75	V
Gate-Source Voltage			V _{GSS}	±20	V
Continuous Drain Current (Note 6) V _{GS} = 10V	Steady State	T _A = +25°C T _A = +70°C	I _D	7.8 6.2	A
	t < 10s	T _A = +25°C T _A = +70°C	I _D	10.5 8.4	A
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I _{DM}	56	A
Maximum Continuous Body Diode Forward Current (Note 6)			I _S	2.1	A
Avalanche Current, L = 0.1mH			I _{AS}	28.8	A
Avalanche Energy, L = 0.1mH			E _{AS}	42.2	mJ

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Total Power Dissipation (Note 5)			P _D	0.9	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady state		R _{θJA}	125	°C/W
	t < 10s			67	
Total Power Dissipation (Note 6)			P _D	2	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady state		R _{θJA}	62	°C/W
	t < 10s			34	
Thermal Resistance, Junction to Case (Note 6)			R _{θJC}	6.9	
Operating and Storage Temperature Range			T _J , T _{STG}	-55 to +150	°C

Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	75	—	—	V	V _{GS} = 0V, I _D = 250µA
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	—	—	1	µA	V _{DS} = 75V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(th)}	1	—	3	V	V _{DS} = V _{GS} , I _D = 250µA
Static Drain-Source On-Resistance	R _{DS(on)}	—	14.6	22	mΩ	V _{GS} = 10V, I _D = 7.2A
		—	20.5	28		V _{GS} = 4.5V, I _D = 6.4A
Diode Forward Voltage	V _{SD}	—	0.72	—	V	V _{GS} = 0V, I _S = 3.2A
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	—	2737	—	pF	V _{DS} = 35V, V _{GS} = 0V, f = 1MHz
Output Capacitance	C _{oss}	—	126	—	pF	
Reverse Transfer Capacitance	C _{rss}	—	96.1	—	pF	
Gate Resistance	R _g	—	0.89	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Total Gate Charge (V _{GS} = 4.5V)	Q _g	—	26.4	—	nC	V _{DS} = 38V, I _D = 7.2A
Total Gate Charge (V _{GS} = 10V)	Q _g	—	56.5	—	nC	
Gate-Source Charge	Q _{gs}	—	12	—	nC	
Gate-Drain Charge	Q _{gd}	—	11.8	—	nC	
Turn-On Delay Time	t _{D(on)}	—	6.1	—	ns	V _{GS} = 10V, V _{DS} = 38V, R _G = 1Ω, I _D = 5.7A
Turn-On Rise Time	t _r	—	5.7	—	ns	
Turn-Off Delay Time	t _{D(off)}	—	19.6	—	ns	
Turn-Off Fall Time	t _f	—	3.9	—	ns	
Body Diode Reverse Recovery Time	t _{rr}	—	26.2	—	ns	I _F = 5.7A, di/dt = 100A/µs
Body Diode Reverse Recovery Charge	Q _{rr}	—	25.2	—	nC	

- Notes: 5. Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.
 6. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate
 7. Short duration pulse test used to minimize self-heating effect.
 8. Guaranteed by design. Not subject to product testing.

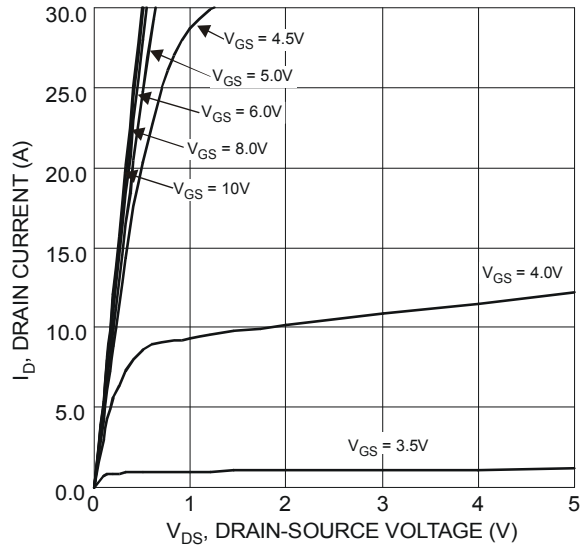


Figure 1 Typical Output Characteristics

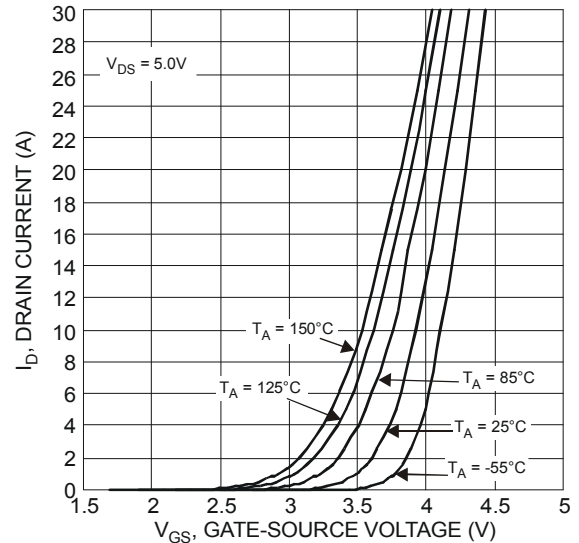


Figure 2 Typical Transfer Characteristics

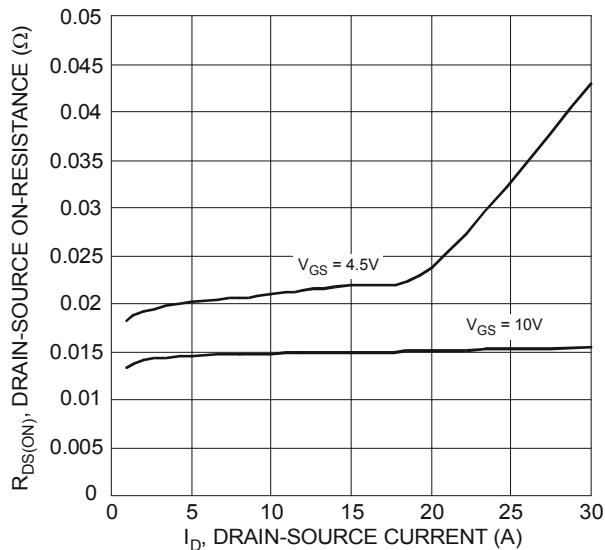


Figure 3 Typical On-Resistance vs. Drain Current and Gate Voltage

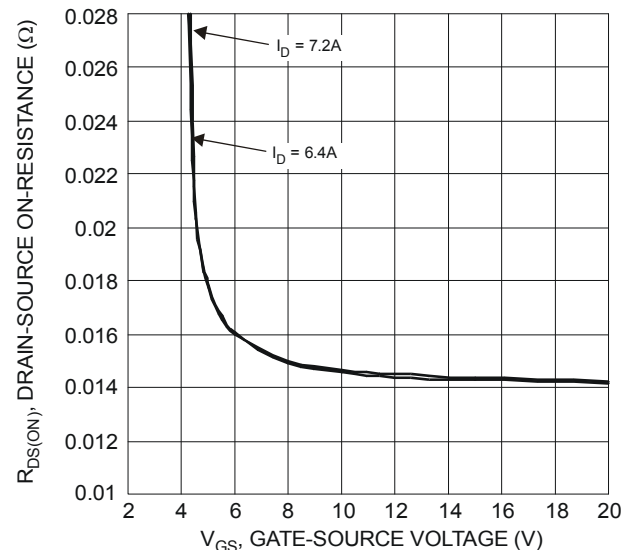


Figure 4 Typical Drain-Source On-Resistance vs. Gate-Source Voltage

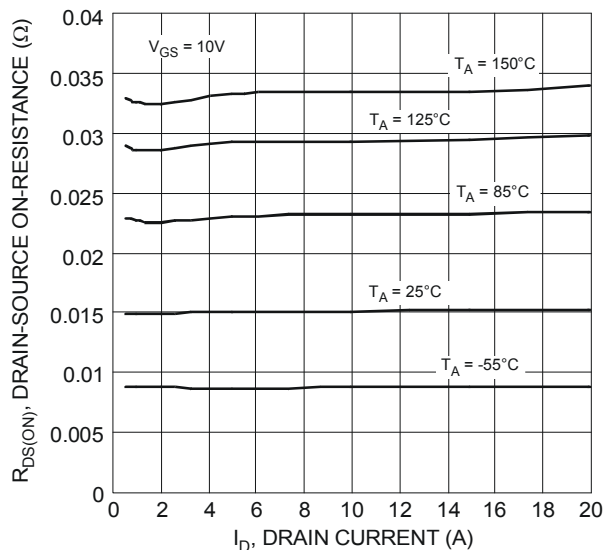


Figure 5 Typical On-Resistance vs. Drain Current and Temperature

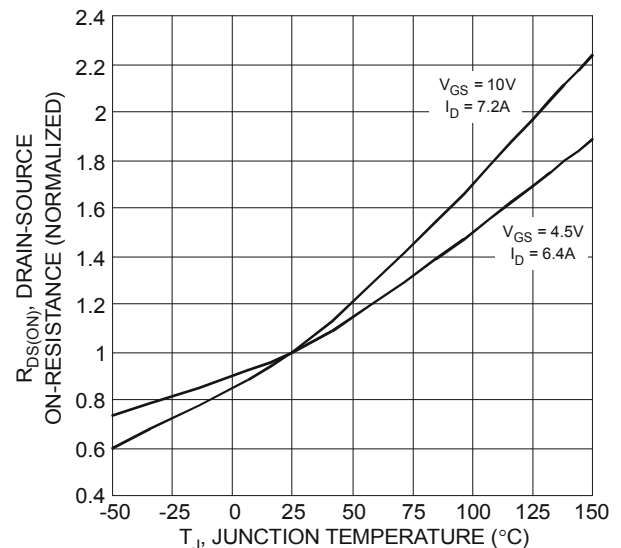


Figure 6 On-Resistance Variation with Temperature

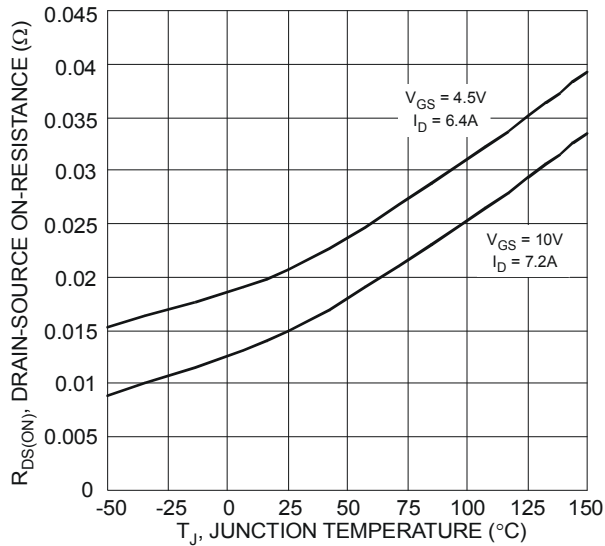


Figure 7 On-Resistance Variation with Temperature

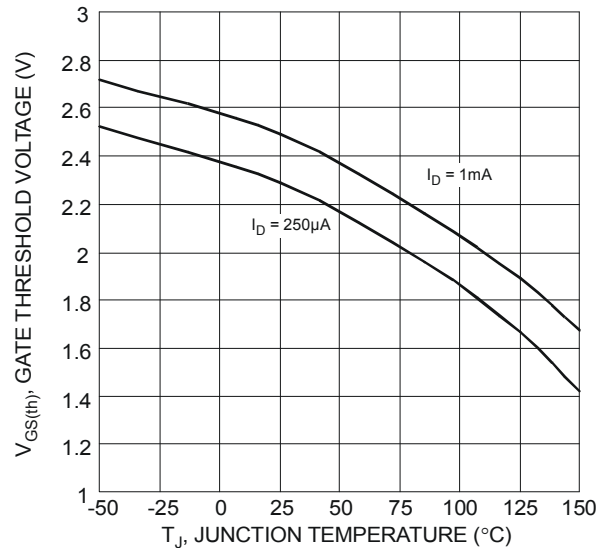


Figure 8 Gate Threshold Variation vs. Ambient Temperature

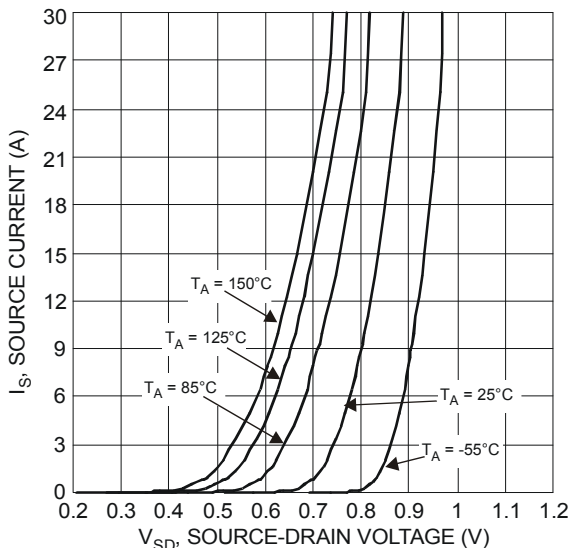


Figure 9 Diode Forward Voltage vs. Current

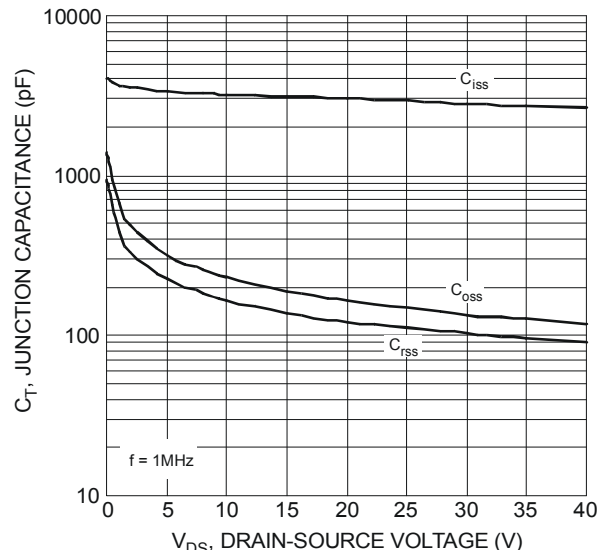


Figure 10 Typical Junction Capacitance

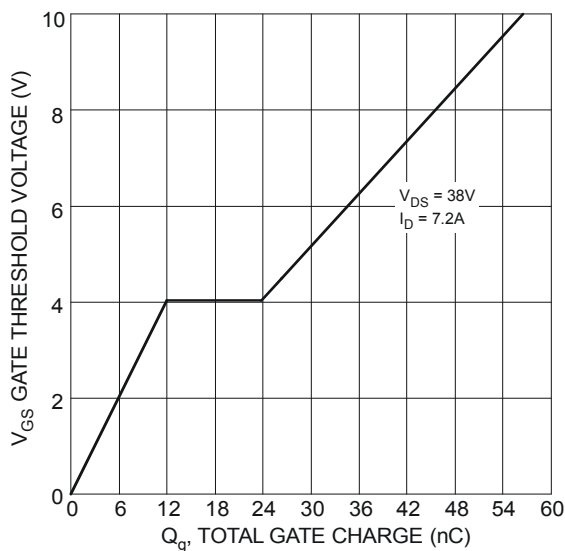


Figure 11 Gate Charge

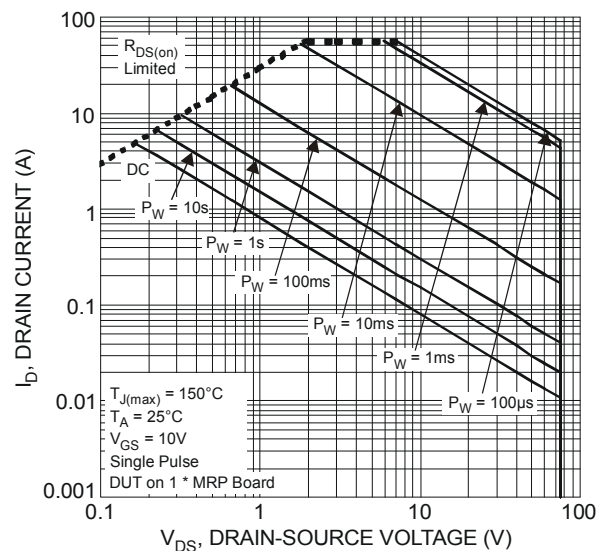
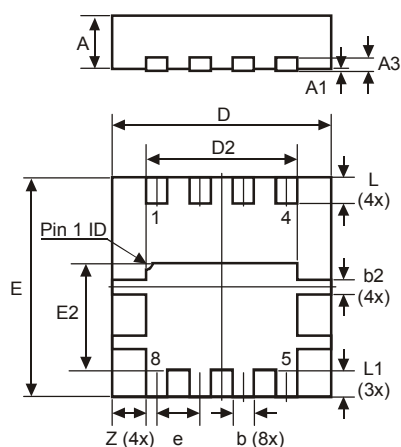


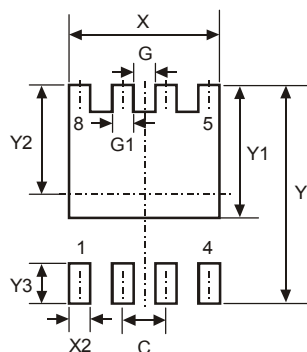
Figure 12 SOA, Safe Operation Area

Please see AP02001 at <http://www.diodes.com/datasheets/ap02001.pdf> for the latest version.



POWERDI® 3333-8			
Dim	Min	Max	Typ
D	3.25	3.35	3.30
E	3.25	3.35	3.30
D2	2.22	2.32	2.27
E2	1.56	1.66	1.61
A	0.75	0.85	0.80
A1	0	0.05	0.02
A3	—	—	0.20(3)
b	0.27	0.37	0.32
b2	—	—	0.20
L	0.35	0.45	0.40
L1	—	—	0.39
e	—	—	0.65
Z	—	—	0.515
All Dimensions in mm			

Please see AP02001 at <http://www.diodes.com/datasheets/ap02001.pdf> for the latest version.



Dimensions	Value (in mm)
C	0.650
G	0.230
G1	0.420
Y	3.700
Y1	2.250
Y2	1.850
Y3	0.700
X	2.370
X2	0.420

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